

PROCEEDINGS OF SPIE

International Conference on Optoelectronic Science and Intelligent Sensing (ICOIS 2025)

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Editors

14–16 March 2025
Changchun, China

Organized by
Changchun College of Electronic Technology (China)

Sponsored by
AEIC—Academic Exchange Information Centre (China)

Published by
SPIE

Volume 13638

Proceedings of SPIE 0277-786X, V. 13638

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Author(s), "Title of Paper," in *International Conference on Optoelectronic Science and Intelligent Sensing (ICOIS 2025)*, edited by Jinhui Song, Weigang Hou, Proc. of SPIE 13638, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X

ISSN: 1996-756X (electronic)

ISBN: 9781510691858

ISBN: 9781510691865 (electronic)

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time)

SPIE.org

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